

Substitute for form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/797,231
		Filing Date	March 10, 2004
		First Named Inventor	Matthew T. Currie
		Art Unit	2812
		Examiner Name	A. G. Ghyka
Sheet	1	of	2
		Attorney Docket Number	ASC-057C1

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No.*	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
	A70*	US-5,166,084	11-24-1992	Pflester		
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	A72*	US-5,981,400	11-09-1999	Lo		
	A73*	US-6,074,919	06-13-2000	Gardner et al.		
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	A75*	US-6,154,475	11-28-2000	Soref et al.		
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	A82*	US-6,846,715	01-25-2005	Fitzgerald et al.		
	A83*	US-7,217,668	05-15-2007	Fitzgerald et al.		
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No.*	Foreign Patent Document Country Code ³ Number ⁴ Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	
	B1	EP-0 587 520	03-16-1994			✓
	B2	JP-2000-031491	01-28-2000			✓

Examiner Signature	/Alexander Ghyka/ (12/10/2008)	Date Considered	
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/Alexander Ghyka/ (12/10/2008)

PTO/SB/08b (09-08)
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/797,231
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		First Named Inventor	Richard Hammond
		Art Unit	2812
		Examiner Name	A. G. Ghyka
		Attorney Docket Number	ASC-057C1
Sheet	2	of	2

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issu/e number(s), publisher, city and/or country where published.	T ²
	C86	Abramo, A. et al., "Mobility Simulation of a Novel Si/SiGe FET Structure," IEEE Electron Device Letters, vol. 17, no. 2, February 1996, pp. 59-61.	
	C87	Hellberg, P.E. et al., "Oxidation of silicon-germanium alloys. I. An experimental study," Journal of Applied Physics, vol. 82, no. 11, December 1, 1997, pp. 5773-5778.	
	C88	International Search Report for Patent Application No. PCT/US 01/24614, dated 3/11/2002, 3 pages.	
	C89	Notice of Assignment of Inter Partes Reexamination Request, Patent No. 6,846,715, July 27, 2006.	
	C90	Office Action in Inter Partes Reexamination, Patent No. 6,846,715, August 30, 2006.	
	C91	Niino, T. et al., "SiGe Passivation for Si MBE Regrowth," Japanese Journal of Applied Physics, vol. 29, no. 9, pp. 1702-1704, September 1990.	
	C92	O'Neill, A.G. et al., "Deep Submicron CMOS Based on Silicon Germanium Technology," IEEE Transactions on Electron Devices, vol. 43, no. 6, June 1996, pp. 911-918.	
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	C94	Request for Inter Partes Reexamination of U.S. Patent No. 6,846,715, June 26, 2006.	
	C95	Wolf, "Silicon Processing for the VLSI Era, vol. 2: Process Integration," pp. 27, 331 (Lattice Press, 1990).	
	C96	Wu et al., "High-Quality Thermal Oxide Grown on High-Temperature-Formed SiGe," 147 J. Electrochemical Soc'y 5, pp. 1962-64 (2000).	

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/Alexander Ghyka/ (12/10/2008)

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /A.G./